

Search Notes

Application/Control No.

10/674,177

Examiner

VanThu Nguyen

Applicant(s)/Patent under
Reexamination

HAN ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	193 o 233 x 233.5 x 189.05 x	8/1/2005	VTN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (see print out history)	8/1/2005	VTN